Application/Control No. Applicant(s)/Patent Under Reexamination 10/789,295 WANG ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 1751 Mark Kopec **U.S. PATENT DOCUMENTS Document Number** Date Classification Name Country Code-Number-Kind Code MM-YYYY 252/301.35 US-2003/0001141 01-2003 Sun et al. Α US-2002/0165305 11-2002 Knudson et al. 524/445 В US-2002/0161101 10-2002 Carroll et al. 524/495 С US-D US-Ε US-F US-G US-Н US-US-US-Κ

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